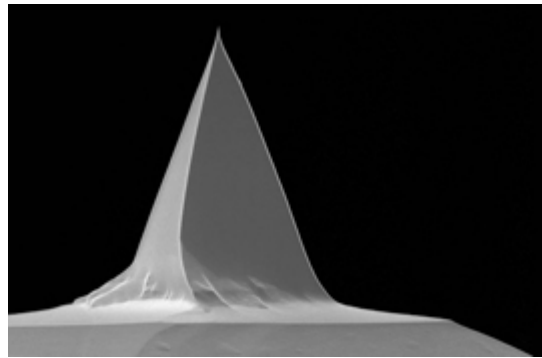


# ANSCM-PA5

ANSCM-PA5 probes are non-contact / tapping mode probes designed for Electronic Force Microscopy applications. These probes are designed for CAFM applications and have a thicker Pt-Ir coating for enhanced lifetime.

## Tip Specifications

- **Coating:** Pt/Ir
- **Material:** Silicon
- **Shape:** Pyramidal
- **Height ( $\mu\text{m}$ ):** 14-16
- **Aspect ratio:** 1.5 - 3.0
- **ROC (nm) :** 55



[ANSCM-PA5](#)

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## Cantilever Specifications

Material: Silicon

Shape : Rectangular

Reflex Pt/Ir

coating : (50+/-5nm)

Parameter	Nominal	Min	Max
k (N/m)	40	25	75
f (kHz)	300.0	200.0	400.0
Length ( $\mu\text{m}$ )	125.0	115.0	135.0
Width ( $\mu\text{m}$ )	35.0	30.0	40.0
Thickness ( $\mu\text{m}$ )	4.50	4.00	5.00